

Notice of References Cited		Application/Control No. 10/656,311	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner Paul D Kim	Art Unit 3729	Page 1 of 1

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	U	"Electrochemical corrosion study of high moment thin film head materials"; Gangopadhyay, S.; Inturi, V.R.; Barnard, J.A.; Parker, M.R.; Saffarian, H.M.; Warren, G.W.; Magnetics, IEEE Transactions on , Volume: 30 , Issue: 6 , Nov 1994; Pages:3918 3920.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.